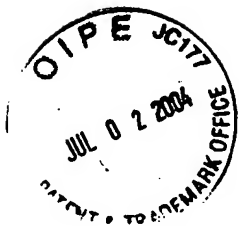


IFW



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: Q76144

Satoshi ARAKAWA

Allowed: April 26, 2004

Appln. No.: 10/634,777

Group Art Unit: 2878

Confirmation No.: 7626

Examiner: Constantine HANNAHER

Filed: August 6, 2003

For: RADIATION IMAGE DETECTING SYSTEM

COMMENTS ON EXAMINER'S STATEMENT FOR REASONS OF ALLOWANCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

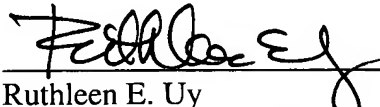
In response to the Examiner's Statement of Reasons for Allowance accompanying the Notice of Allowability dated April 26, 2004, Applicant submits the following comments:

COMMENTS

Applicant submits that the scope of the claims should be governed by the actual claim language and not by the Examiner's reasons for allowance. In particular, it is improper for the Examiner to impart thickness limitations on the claims based on the specification.

Respectfully submitted,

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Date: July 2, 2004